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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	36MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, PDR, POR, PVD, PWM, Temp Sensor, WDT
Number of I/O	51
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f101rct6tr

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Table 4. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM2, TIM3, TIM4, TIM5	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	No
TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

General-purpose timers (TIMx)

There are up to 4 synchronizable general-purpose timers (TIM2, TIM3, TIM4 and TIM5) embedded in the STM32F101xC, STM32F101xD and STM32F101xE access line devices. These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture/output compare, PWM or one-pulse mode output. This gives up to 16 input captures / output compares / PWMs on the largest packages.

The general-purpose timers can work together with the advanced-control timer via the Timer Link feature for synchronization or event chaining. Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs. They all have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger generation. They can also be used as a generic 16-bit time base.

Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

2.3.22 ADC (analog to digital converter)

A 12-bit analog-to-digital converter is embedded into STM32F101xC, STM32F101xD and STM32F101xE access line devices. It has up to 16 external channels, performing conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADC can be served by the DMA controller.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

The events generated by the general-purpose timers (TIMx) can be internally connected to the ADC start trigger and injection trigger, respectively, to allow the application to synchronize A/D conversion and timers.

2.3.23 DAC (digital-to-analog converter)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in inverting configuration.

This dual digital Interface supports the following features:

- two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- left or right data alignment in 12-bit mode
- synchronized update capability
- noise-wave generation
- triangular-wave generation
- dual DAC channel independent or simultaneous conversions
- DMA capability for each channel
- external triggers for conversion
- input voltage reference V_{REF+}

Seven DAC trigger inputs are used in the STM32F101xC, STM32F101xD and STM32F101xE access line family. The DAC channels are triggered through the timer update outputs that are also connected to different DMA channels.

2.3.24 Temperature sensor

The temperature sensor has to generate a voltage that varies linearly with temperature. The conversion range is between $2\text{ V} < V_{DDA} < 3.6\text{ V}$. The temperature sensor is internally connected to the ADC_IN16 input channel which is used to convert the sensor output voltage into a digital value.

2.3.25 Serial wire JTAG debug port (SWJ-DP)

The ARM® SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target. The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

2.3.26 Embedded Trace Macrocell™

The ARM® Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F10xxx through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer running debugger software. TPA hardware is commercially available from common development tool vendors. It operates with third party debugger software tools.

Table 5. STM32F101xC/STM32F101xD/STM32F101xE pin definitions (continued)

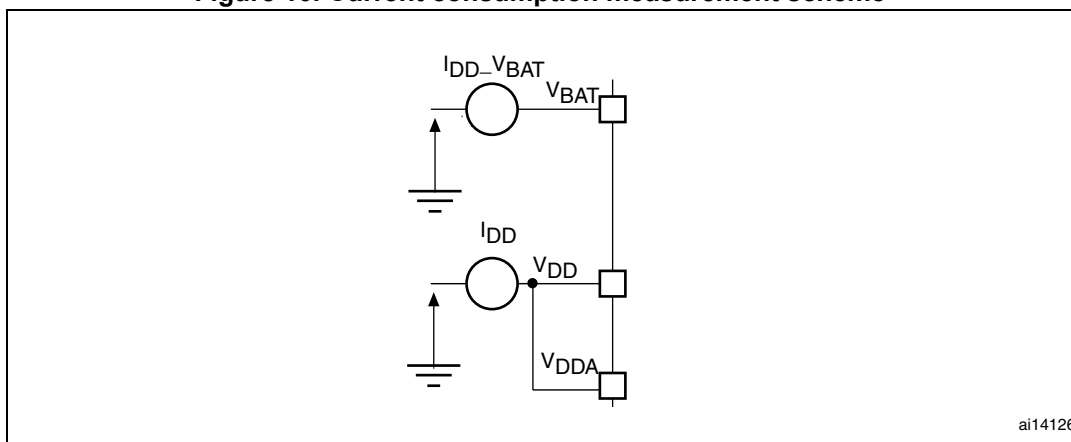
Pins			Pin name	Type ⁽¹⁾	I / O Level ⁽²⁾	Main function ⁽³⁾ (after reset)	Alternate functions ⁽⁴⁾	
LQFP144	LQFP64	LQFP100					Default	Remap
12	-	-	PF2	I/O	FT	PF2	FSMC_A2	-
13	-	-	PF3	I/O	FT	PF3	FSMC_A3	-
14	-	-	PF4	I/O	FT	PF4	FSMC_A4	-
15	-	-	PF5	I/O	FT	PF5	FSMC_A5	-
16	-	10	V _{SS_5}	S	-	V _{SS_5}	-	-
17	-	11	V _{DD_5}	S	-	V _{DD_5}	-	-
18	-	-	PF6	I/O	-	PF6	FSMC_NIORD	-
19	-	-	PF7	I/O	-	PF7	FSMC_NREG	-
20	-	-	PF8	I/O	-	PF8	FSMC_NIOWR	-
21	-	-	PF9	I/O	-	PF9	FSMC_CD	-
22	-	-	PF10	I/O	-	PF10	FSMC_INTR	-
23	5	12	OSC_IN	I	-	OSC_IN	-	PD0 ⁽⁷⁾
24	6	13	OSC_OUT	O	-	OSC_OUT	-	PD1 ⁽⁷⁾
25	7	14	NRST	I/O	-	NRST	-	-
26	8	15	PC0	I/O	-	PC0	ADC_IN10	-
27	9	16	PC1	I/O	-	PC1	ADC_IN11	-
28	10	17	PC2	I/O	-	PC2	ADC_IN12	-
29	11	18	PC3	I/O	-	PC3	ADC_IN13	-
30	12	19	V _{SSA}	S	-	V _{SSA}	-	-
31	-	20	V _{REF-}	S	-	V _{REF-}	-	-
32	-	21	V _{REF+}	S	-	V _{REF+}	-	-
33	13	22	V _{DDA}	S	-	V _{DDA}	-	-
34	14	23	PA0-WKUP	I/O	-	PA0	WKUP/ USART2_CTS ⁽⁸⁾ / ADC_IN0/TIM5_CH1/ TIM2_CH1_ETR ⁽⁸⁾	-
35	15	24	PA1	I/O	-	PA1	USART2_RTS ⁽⁸⁾ / ADC_IN1/TIM5_CH2 TIM2_CH2 ⁽⁸⁾	-
36	16	25	PA2	I/O	-	PA2	USART2_TX ⁽⁸⁾ / TIM5_CH3/ADC_IN2/ TIM2_CH3 ⁽⁸⁾	-

4 Memory mapping

The memory map is shown in [Figure 6](#).

5.1.7 Current consumption measurement

Figure 10. Current consumption measurement scheme



5.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 7: Voltage characteristics](#), [Table 8: Current characteristics](#), and [Table 9: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 7. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
$V_{DD} - V_{SS}$	External main supply voltage (including V_{DDA} and V_{DD}) ⁽¹⁾	-0.3	4.0	V
$V_{IN}^{(2)}$	Input voltage on five volt tolerant pin	$V_{SS} - 0.3$	$V_{DD} + 4.0$	
	Input voltage on any other pin	$V_{SS} - 0.3$	4.0	
$ \Delta V_{DDx} $	Variations between different V_{DD} power pins	-	50	mV
$ V_{SSx} - V_{SS} $	Variations between all the different ground pins	-	50	
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	see Section 5.3.12: Absolute maximum ratings (electrical sensitivity)		

1. All main power (V_{DD} , V_{DDA}) and ground (V_{SS} , V_{SSA}) pins must always be connected to the external power supply, in the permitted range.
2. V_{IN} maximum must always be respected. Refer to [Table 8: Current characteristics](#) for the maximum allowed injected current values.

Figure 11. Typical current consumption in Run mode versus frequency (at 3.6 V) - code with data processing running from RAM, peripherals enabled

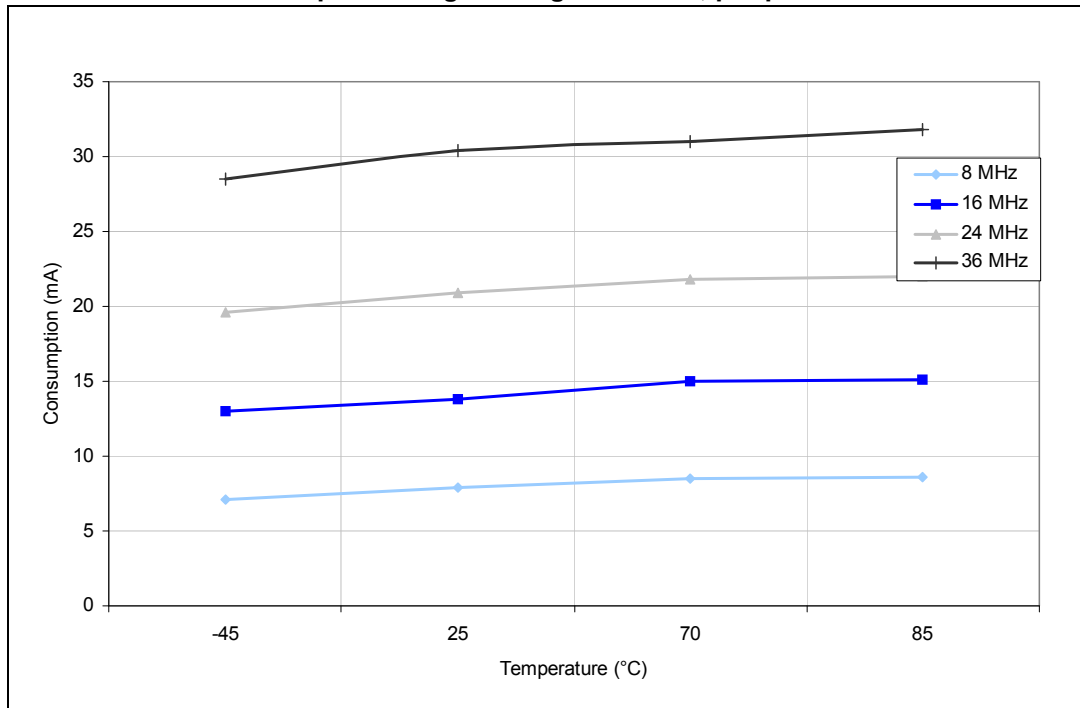


Figure 12. Typical current consumption in Run mode versus frequency (at 3.6 V) - code with data processing running from RAM, peripherals disabled

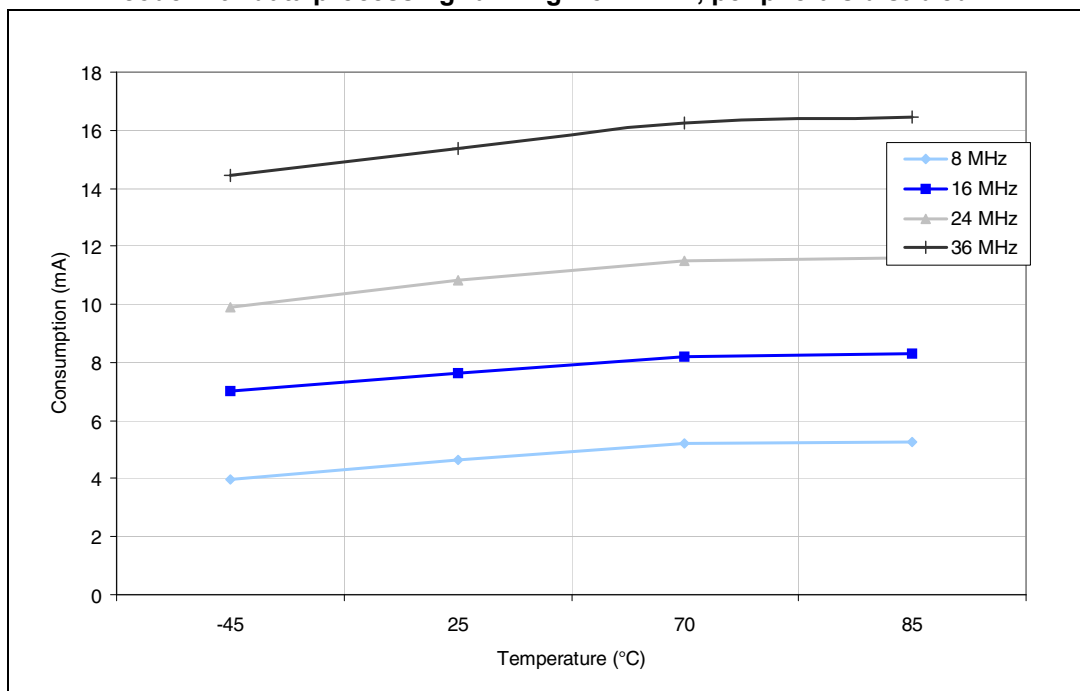


Table 16. Maximum current consumption in Sleep mode, code running from Flash or RAM

Symbol	Parameter	Conditions	f _{HCLK}	Max ⁽¹⁾	Unit
				T _A = 85 °C	
I _{DD}	Supply current in Sleep mode	External clock ⁽²⁾ all peripherals enabled	36 MHz	24	mA
			24 MHz	17	
			16 MHz	12.5	
			8 MHz	8	
		External clock ⁽²⁾ , all peripherals disabled	36 MHz	6	
			24 MHz	5	
			16 MHz	4.5	
			8 MHz	4	

1. Guaranteed by characterization results, tested in production at V_{DD} max, f_{HCLK} max with peripherals enabled.

2. External clock is 8 MHz and PLL is on when f_{HCLK} > 8 MHz.

Table 17. Typical and maximum current consumptions in Stop and Standby modes

Symbol	Parameter	Conditions	Typ ⁽¹⁾			Max	Unit
			V _{DD} / V _{BAT} = 2.0 V	V _{DD} / V _{BAT} = 2.4 V	V _{DD} /V _{BA} T = 3.3 V	T _A = 85 °C	
I _{DD}	Supply current in Stop mode	Regulator in Run mode, Low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	-	34.5	35	379	μA
		Regulator in Low-power mode, Low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	-	24.5	25	365	
	Supply current in Standby mode	Low-speed internal RC oscillator and independent watchdog ON	-	3	3.8	-	
		Low-speed internal RC oscillator ON, independent watchdog OFF	-	2.8	3.6	-	
		Low-speed internal RC oscillator and independent watchdog OFF, low-speed oscillator and RTC OFF	-	1.9	2.1	5 ⁽²⁾	
I _{DD_VBAT}	Backup domain supply current	Low-speed oscillator and RTC ON	1.05	1.1	1.4	2 ⁽²⁾	

1. Typical values are measured at T_A = 25 °C.

2. Guaranteed by characterization results, not tested in production.

Typical current consumption

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at V_{DD} or V_{SS} (no load)
- All peripherals are disabled except if it is explicitly mentioned
- The Flash access time is adjusted to f_{HCLK} frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 36 MHz)
- Prefetch is on (reminder: this bit must be set before clock setting and bus prescaling)
- When the peripherals are enabled $f_{PCLK1} = f_{HCLK}/4$, $f_{PCLK2} = f_{HCLK}/2$, $f_{ADCCLK} = f_{PCLK2}/4$
- When the peripherals are enabled $f_{PCLK1} = f_{HCLK}$, $f_{PCLK2} = f_{HCLK}$, $f_{ADCCLK} = f_{PCLK2}/2$

The parameters given in [Table 18](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 10](#).

Table 18. Typical current consumption in Run mode, code with data processing running from Flash

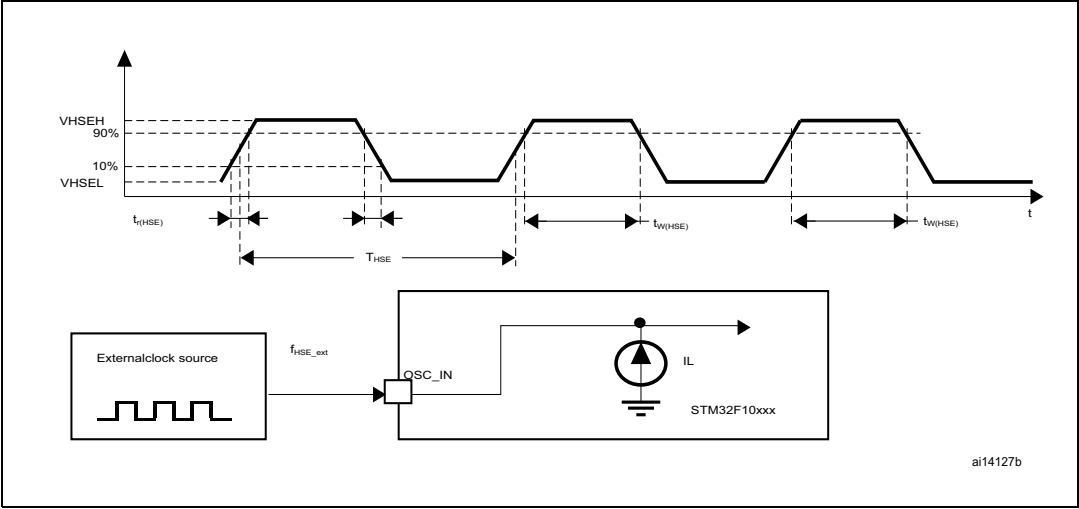
Symbol	Parameter	Conditions	f_{HCLK}	Typ ⁽¹⁾	Typ ⁽¹⁾	Unit
				All peripherals enabled ⁽²⁾	All peripherals disabled	
I_{DD}	Supply current in Run mode	External clock ⁽³⁾	36 MHz	26.6	16.2	mA
			24 MHz	18.5	11.4	
			16 MHz	12.8	8.2	
			8 MHz	7.2	5	
			4 MHz	4.2	3.1	
			2 MHz	2.7	2.1	
			1 MHz	2	1.7	
			500 kHz	1.6	1.4	
			125 kHz	1.3	1.2	
		Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency	36 MHz	26	15.6	
			24 MHz	17.9	10.8	
			16 MHz	12.2	7.6	
			8 MHz	6.6	4.4	
			4 MHz	3.6	2.5	
			2 MHz	2.1	1.5	
			1 MHz	1.4	1.1	
			500 kHz	1	0.8	
			125 kHz	0.7	0.6	

1. Typical values are measures at $T_A = 25\text{ }^{\circ}\text{C}$, $V_{DD} = 3.3\text{ V}$.

2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC_CR2 register).

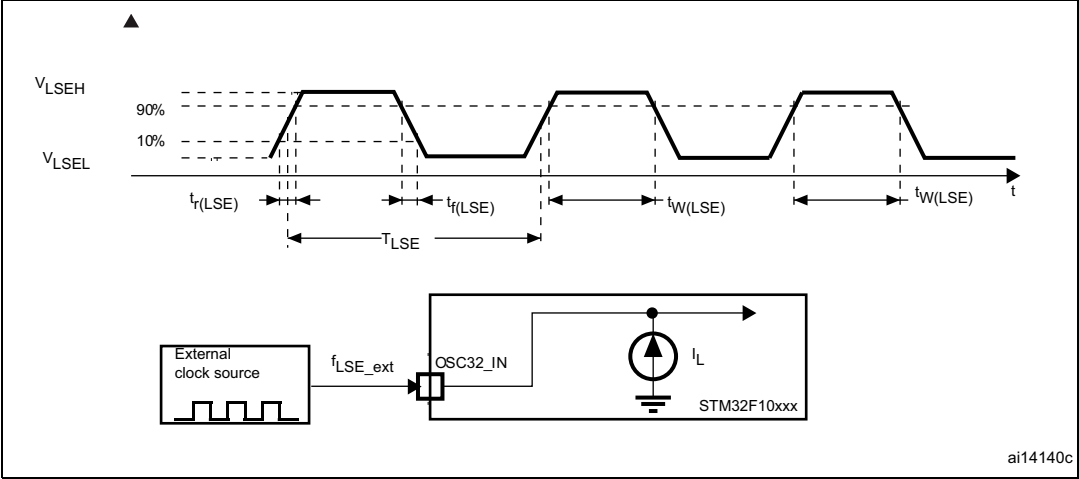
3. External clock is 8 MHz and PLL is on when $f_{HCLK} > 8\text{ MHz}$.

Figure 17. High-speed external clock source AC timing diagram



ai14127b

Figure 18. Low-speed external clock source AC timing diagram



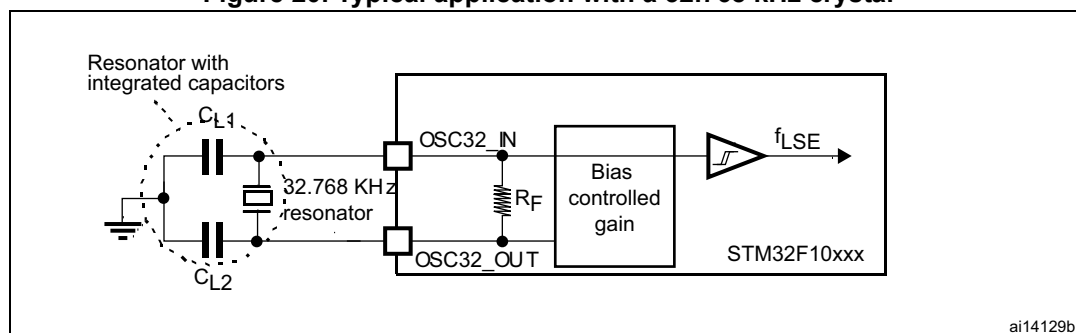
ai14140c

Note: For C_{L1} and C_{L2} , it is recommended to use high-quality ceramic capacitors in the 5 pF to 15 pF range selected to match the requirements of the crystal or resonator. C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2} . Load capacitance C_L has the following formula: $C_L = C_{L1} \times C_{L2} / (C_{L1} + C_{L2}) + C_{stray}$ where C_{stray} is the pin capacitance and board or trace PCB-related capacitance. Typically, it is between 2 pF and 7 pF.

Caution: To avoid exceeding the maximum value of C_{L1} and C_{L2} (15 pF) it is strongly recommended to use a resonator with a load capacitance $C_L \leq 7$ pF. Never use a resonator with a load capacitance of 12.5 pF.

Example: if you choose a resonator with a load capacitance of $C_L = 6$ pF, and $C_{stray} = 2$ pF, then $C_{L1} = C_{L2} = 8$ pF.

Figure 20. Typical application with a 32.768 kHz crystal



5.3.7 Internal clock source characteristics

The parameters given in [Table 25](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 10](#).

High-speed internal (HSI) RC oscillator

Table 25. HSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
f _{HSI}	Frequency	-		-	8	-	MHz
DuCy _(HSI)	Duty cycle	-		45	-	55	%
ACC _{HSI}	Accuracy of the HSI oscillator	User-trimmed with the RCC_CR register ⁽²⁾		-	-	1 ⁽³⁾	%
		Factory-calibrated ⁽⁴⁾	T _A = −40 to 105 °C	−2	-	2.5	%
			T _A = −10 to 85 °C	−1.5	-	2.2	%
			T _A = 0 to 70 °C	−1.3	-	2	%
			T _A = 25 °C	−1.1	-	1.8	%
t _{su(HSI)} ⁽⁴⁾	HSI oscillator startup time	-		1	-	2	μs
I _{DD(HSI)} ⁽⁴⁾	HSI oscillator power consumption	-		-	80	100	μA

1. $V_{DD} = 3.3$ V, $T_A = -40$ to 85 °C unless otherwise specified.

Table 35. Synchronous multiplexed NOR/PSRAM read timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(CLK)}$	FSMC_CLK period	55.5	-	ns
$t_{d(CLKL-NExL)}$	FSMC_CLK low to FSMC_NEx low (x = 0...2)	-	1.5	ns
$t_{d(CLKL-NExH)}$	FSMC_CLK low to FSMC_NEx high (x = 0...2)	2	-	ns
$t_{d(CLKL-NADV_L)}$	FSMC_CLK low to FSMC_NADV low	-	4	ns
$t_{d(CLKL-NADV_H)}$	FSMC_CLK low to FSMC_NADV high	5	-	ns
$t_{d(CLKL-AV)}$	FSMC_CLK low to FSMC_Ax valid (x = 16...25)	-	0	ns
$t_{d(CLKL-AIV)}$	FSMC_CLK low to FSMC_Ax invalid (x = 16...25)	2	-	ns
$t_{d(CLKH-NOEL)}$	FSMC_CLK high to FSMC_NOE low	-	1	ns
$t_{d(CLKL-NOEH)}$	FSMC_CLK low to FSMC_NOE high	0.5	-	ns
$t_{d(CLKL-ADV)}$	FSMC_CLK low to FSMC_AD[15:0] valid	-	12	ns
$t_{d(CLKL-ADIV)}$	FSMC_CLK low to FSMC_AD[15:0] invalid	0	-	ns
$t_{su(ADV-CLKH)}$	FSMC_A/D[15:0] valid data before FSMC_CLK high	6	-	ns
$t_h(CLKH-ADV)$	FSMC_A/D[15:0] valid data after FSMC_CLK high	0	-	ns
$t_{su(NWAITV-CLKH)}$	FSMC_NWAIT valid before FSMC_CLK high	8	-	ns
$t_h(CLKH-NWAITV)$	FSMC_NWAIT valid after FSMC_CLK high	2	-	ns

1. $C_L = 15$ pF.

2. Guaranteed by characterization results, not tested in production..

2. Guaranteed by characterization results, not tested in production.

Figure 28. Synchronous non-multiplexed PSRAM write timings

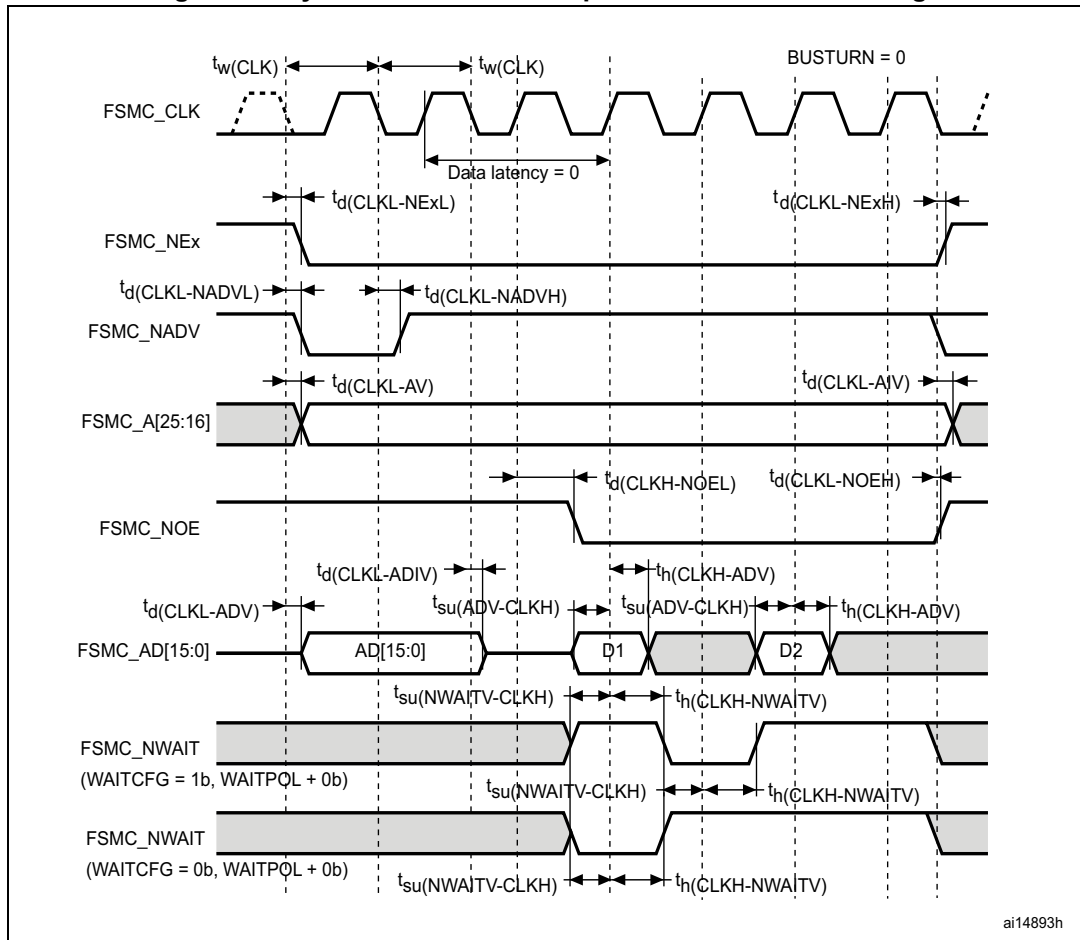
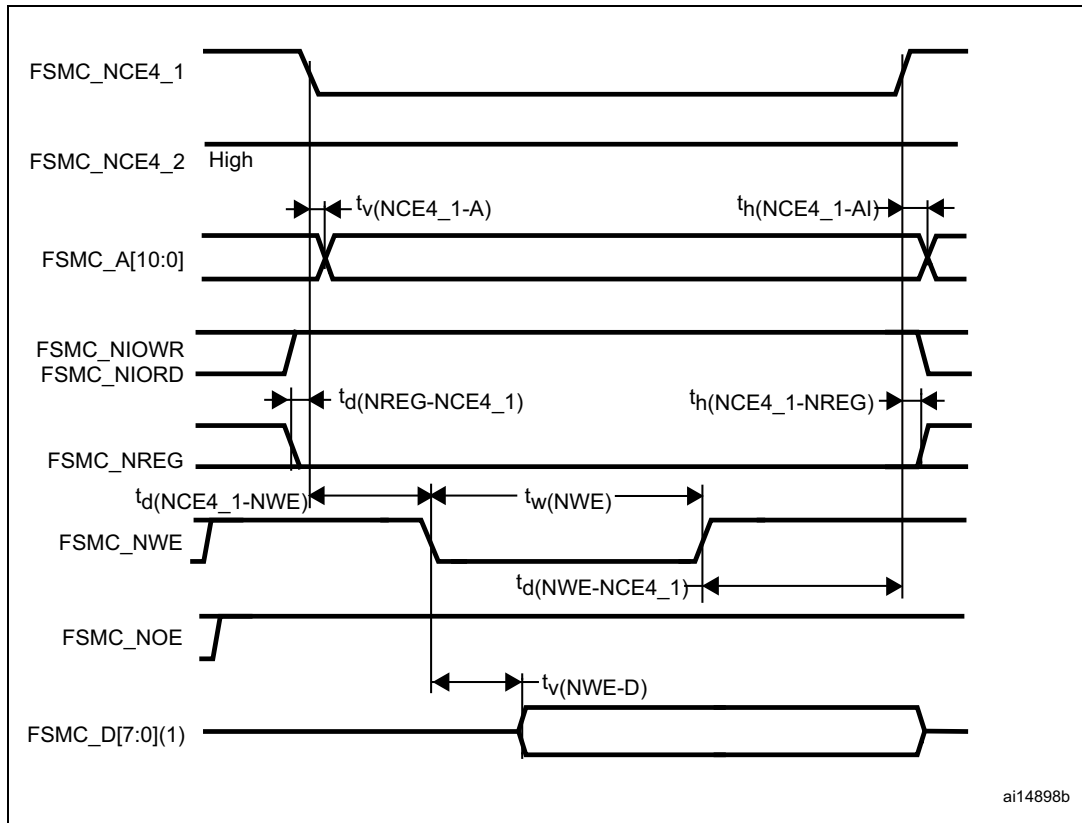


Table 38. Synchronous non-multiplexed PSRAM write timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_w(\text{CLK})$	FSMC_CLK period	55.5	-	ns
$t_d(\text{CLKL-NExL})$	FSMC_CLK low to FSMC_NEx low (x = 0...2)	-	2	ns
$t_d(\text{CLKL-NExH})$	FSMC_CLK low to FSMC_NEx high (x = 0...2)	2	-	ns
$t_d(\text{CLKL-NADV})$	FSMC_CLK low to FSMC_NADV low	-	4	ns
$t_d(\text{CLKL-NADVH})$	FSMC_CLK low to FSMC_NADV high	5	-	ns
$t_d(\text{CLKL-AV})$	FSMC_CLK low to FSMC_Ax valid (x = 16...25)	-	0	ns
$t_d(\text{CLKL-AIV})$	FSMC_CLK low to FSMC_Ax invalid (x = 16...25)	2	-	ns
$t_d(\text{CLKL-NWEL})$	FSMC_CLK low to FSMC_NWE low	-	1	ns
$t_d(\text{CLKL-NWEH})$	FSMC_CLK low to FSMC_NWE high	1	-	ns
$t_d(\text{CLKL-Data})$	FSMC_D[15:0] valid data after FSMC_CLK low	-	6	ns
$t_{su}(\text{NWAITV-CLKH})$	FSMC_NWAIT valid before FSMC_CLK high	7	-	ns

Figure 32. PC Card/CompactFlash controller waveforms for attribute memory write access

1. Only data bits 0...7 are driven (bits 8...15 remains HiZ).

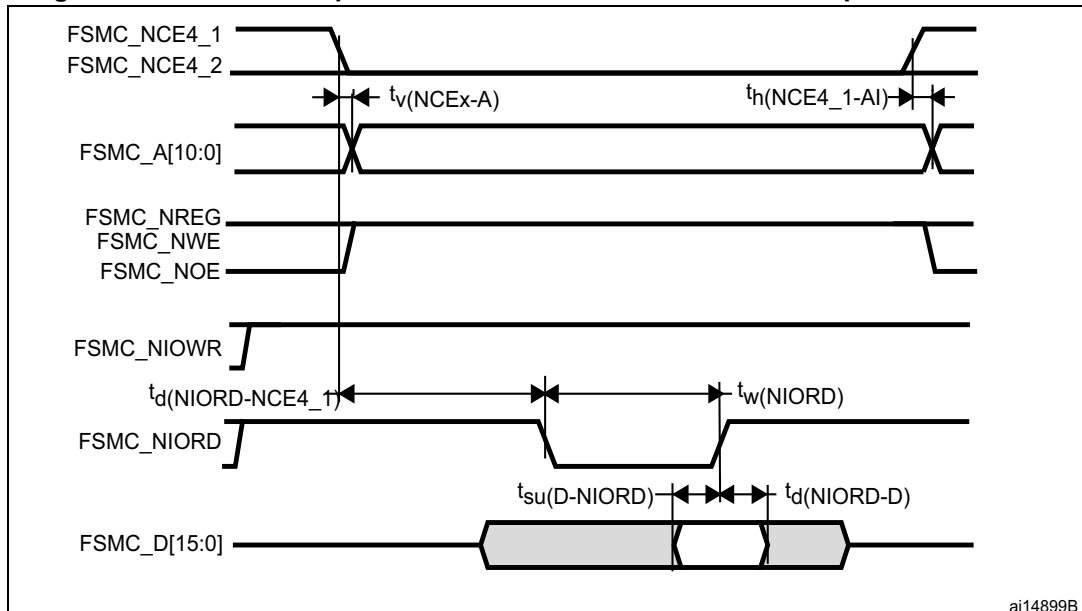
Figure 33. PC Card/CompactFlash controller waveforms for I/O space read access

Figure 41. 5 V tolerant I/O input characteristics - CMOS port

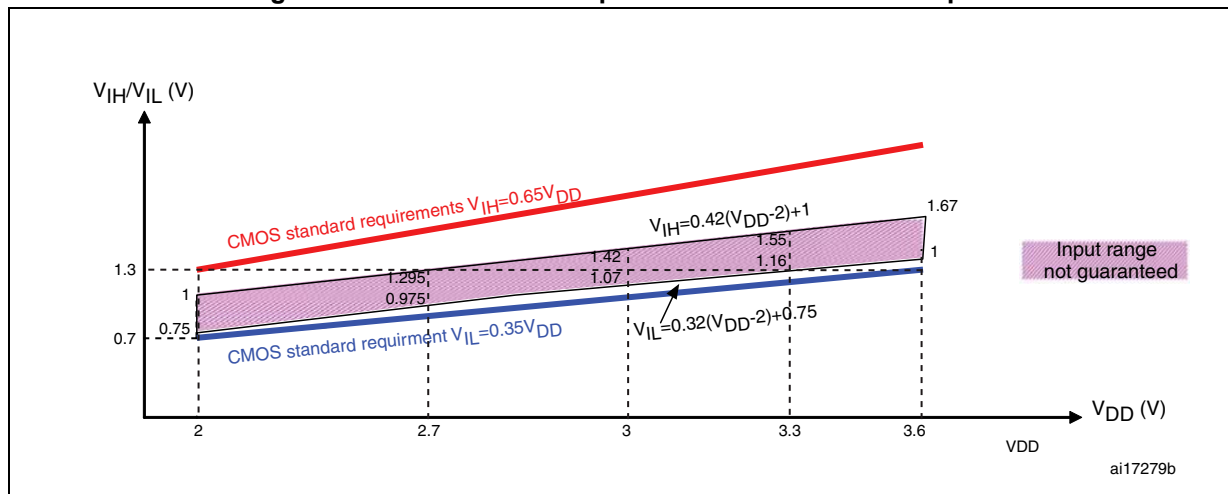
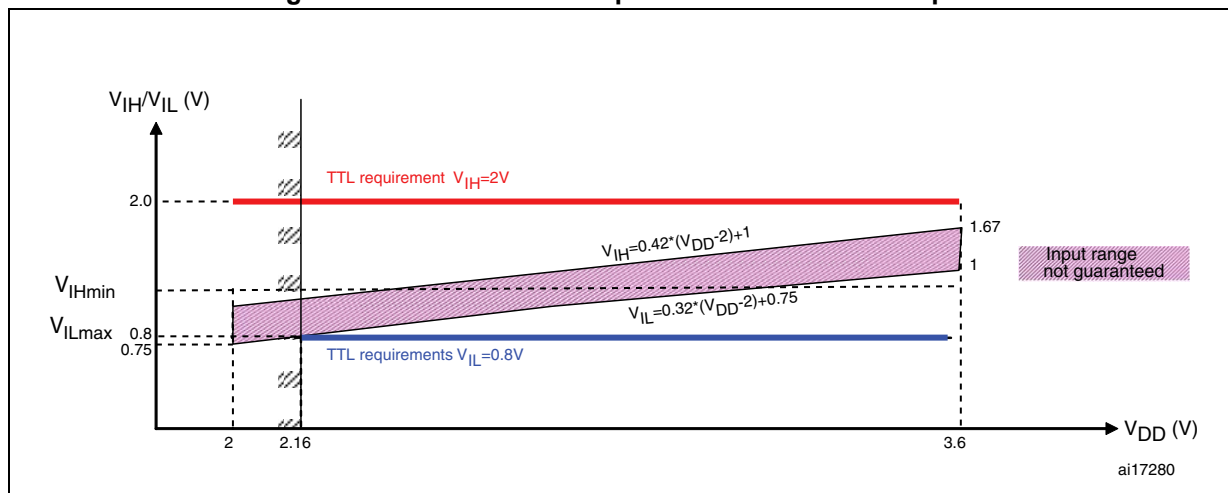


Figure 42. 5 V tolerant I/O input characteristics - TTL port



Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to ± 8 mA, and sink or source up to ± 20 mA (with a relaxed V_{OL}/V_{OH}) except PC13, PC14 and PC15 which can sink or source up to ± 3 mA. When using the GPIOs PC13 to PC15 in output mode, the speed should not exceed 2 MHz with a maximum load of 30 pF.

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 5.2](#):

- The sum of the currents sourced by all the I/Os on V_{DD} , plus the maximum Run consumption of the MCU sourced on V_{DD} , cannot exceed the absolute maximum rating I_{VDD} (see [Table 8](#)).
- The sum of the currents sunk by all the I/Os on V_{SS} plus the maximum Run consumption of the MCU sunk on V_{SS} cannot exceed the absolute maximum rating I_{VSS} (see [Table 8](#)).

5.3.16 TIM timer characteristics

The parameters given in [Table 50](#) are guaranteed by design.

Refer to [Section 5.3.13: I/O current injection characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 50. TIMx⁽¹⁾ characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	27.8	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	-	0	$f_{TIMxCLK}/2$	MHz
		$f_{TIMxCLK} = 36\text{ MHz}$	0	18	MHz
Res_{TIM}	Timer resolution	-	-	16	bit
$t_{COUNTER}$	16-bit counter clock period when internal clock is selected	-	1	65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	0.0278	1820	μs
t_{MAX_COUNT}	Maximum possible count	-	-	65536×65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	-	119.2	s

1. TIMx is used as a general term to refer to the TIM1, TIM2, TIM3 and TIM4 timers.

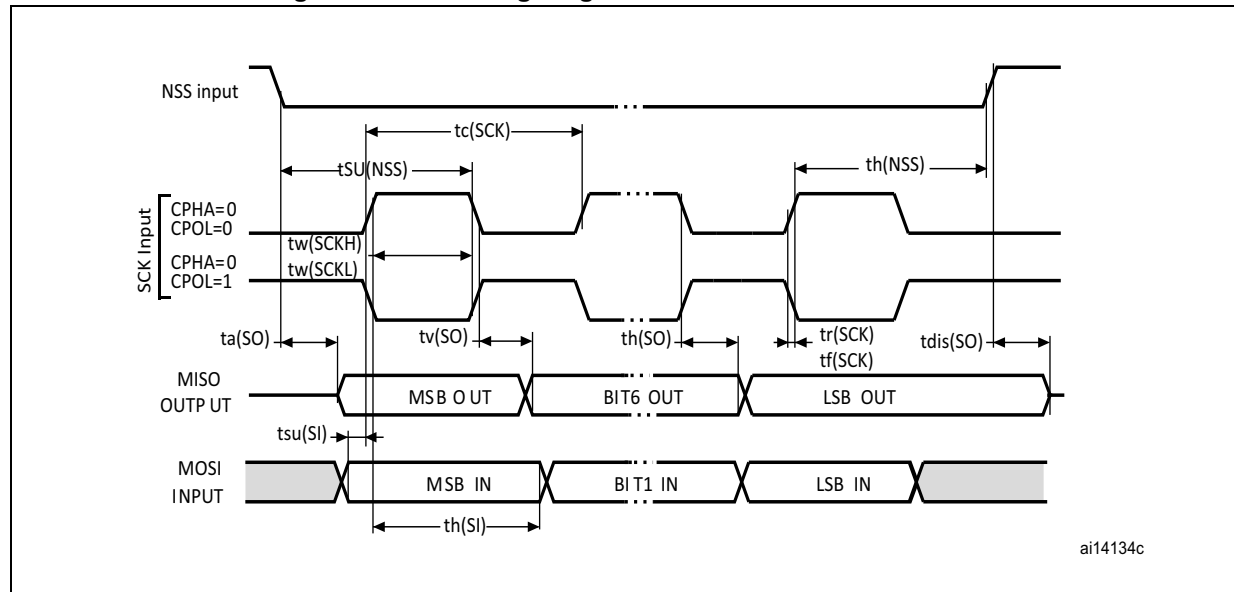
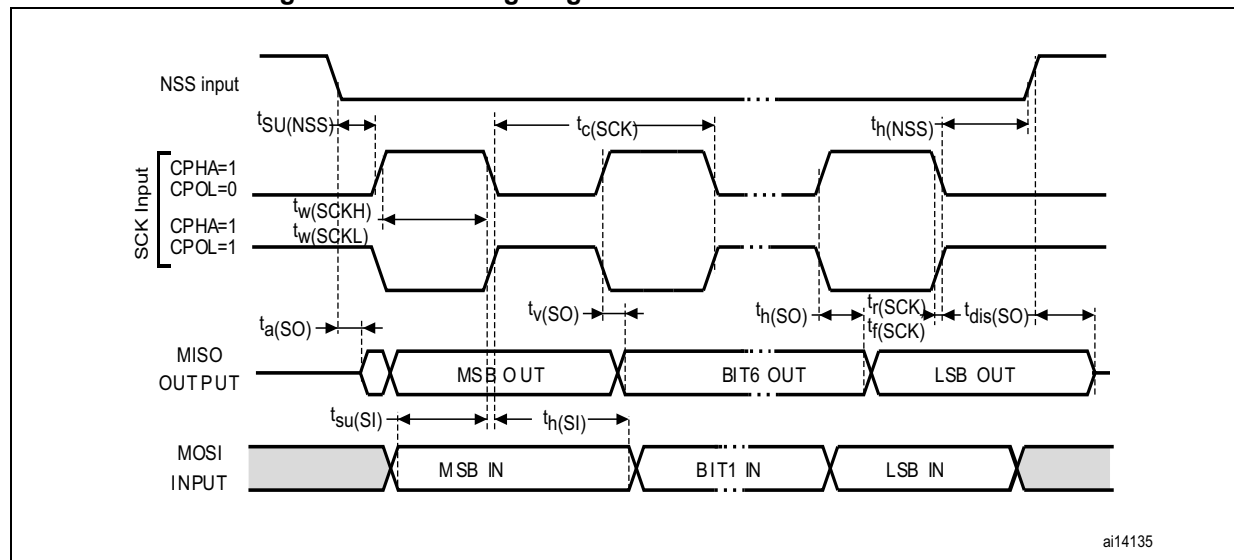
5.3.17 Communications interfaces

I²C interface characteristics

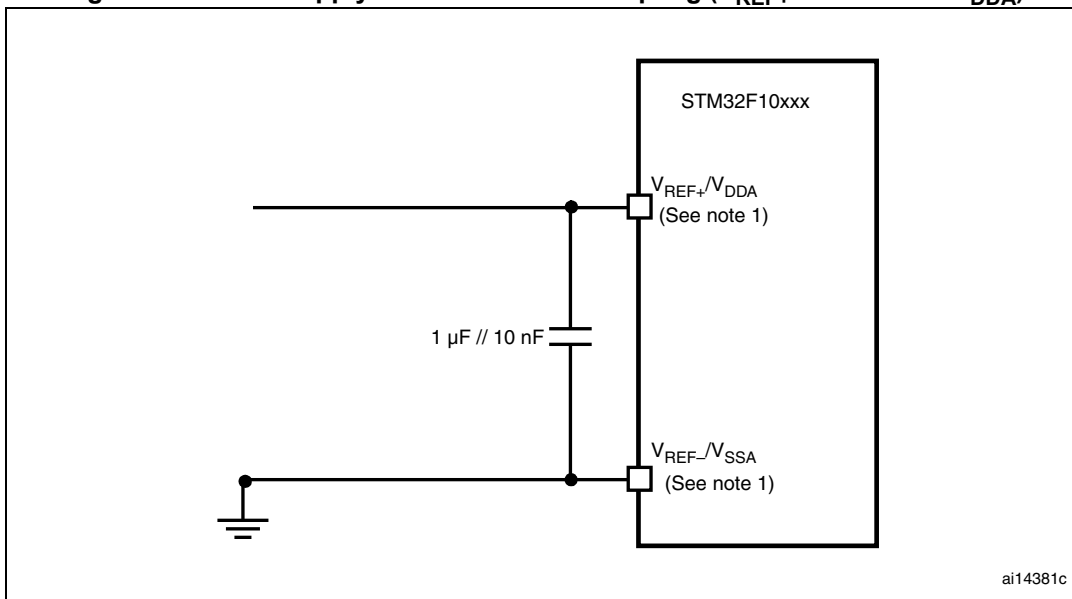
The STM32F101xC, STM32F101xD and STM32F101xE access line I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but is still present.

The I²C characteristics are described in [Table 51](#). Refer also to [Section 5.3.13: I/O current injection characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

Figure 46. SPI timing diagram - slave mode and CPHA=0

Figure 47. SPI timing diagram - slave mode and CPHA=1⁽¹⁾

1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

Figure 52. Power supply and reference decoupling (V_{REF+} connected to V_{DDA})

1. V_{REF+} and V_{REF-} inputs are available only on 100-pin packages.

5.3.19 DAC electrical specifications

Table 59. DAC characteristics

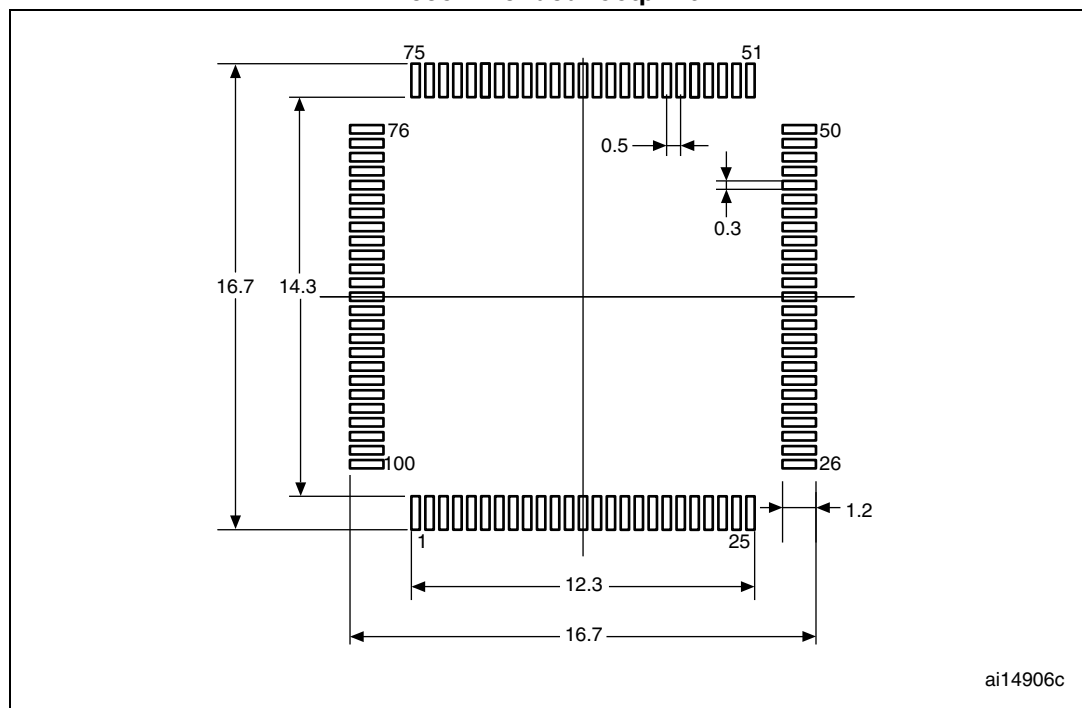
Symbol	Parameter	Min	Typ	Max ⁽¹⁾	Unit	Comments
V_{DDA}	Analog supply voltage	2.4	-	3.6	V	
V_{REF+}	Reference supply voltage	2.4	-	3.6	V	V_{REF+} must always be below V_{DDA}
V_{SSA}	Ground	0	-	0	V	
$R_{LOAD}^{(2)}$	Resistive load with buffer ON	5	-	-	k Ω	
$R_O^{(2)}$	Impedance output with buffer OFF	-	-	15	k Ω	When the buffer is OFF, the minimum resistive load between DAC_OUT and V_{SS} to have a 1% accuracy is 1.5 M Ω
$C_{LOAD}^{(2)}$	Capacitive load	-	-	50	pF	Maximum capacitive load at DAC_OUT pin (when the buffer is ON).
DAC_OUT min ⁽²⁾	Lower DAC_OUT voltage with buffer ON	0.2	-	-	V	It gives the maximum output excursion of the DAC. It corresponds to 12-bit input code (0x0E0) to (0xF1C) at $V_{REF+} = 3.6\ V$ and (0x155) and (0xEAB) at $V_{REF+} = 2.4\ V$.
DAC_OUT max ⁽²⁾	Higher DAC_OUT voltage with buffer ON	-	-	$V_{DDA} - 0.2$	V	
DAC_OUT min ⁽²⁾	Lower DAC_OUT voltage with buffer OFF	-	0.5	-	mV	It gives the maximum output excursion of the DAC.
DAC_OUT max ⁽²⁾	Higher DAC_OUT voltage with buffer OFF	-	-	$V_{REF+} - 1\text{LSB}$	V	

Table 62. LQPF100 – 14 x 14 mm, 100-pin low-profile quad flat package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
E3	-	12.000	-	-	0.4724	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 58. LQFP100 - 100-pin, 14 x 14 mm low-profile quad flat recommended footprint



1. Dimensions are in millimeters.